

[54] **INSIDE MICROMETER**

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[**] **Term:** 14 Years

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[51] **Int. Cl.** D10-04

[52] **U.S. Cl.** D10/73

[58] **Field of Search** D10/70-71,
D10/73, 74; 33/178 R

[56] **References Cited**

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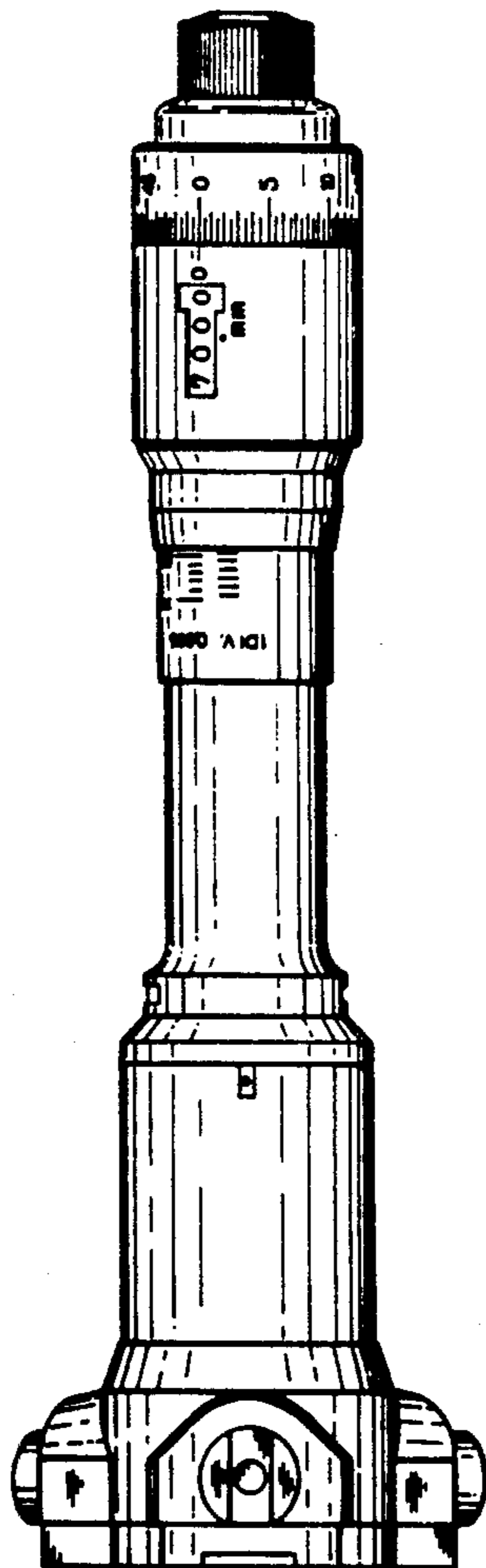
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[57] **CLAIM**

The ornamental design for an inside micrometer, as shown.

DESCRIPTION

FIG. 1 is a front elevational view of an inside micrometer showing my new design;
FIG. 2 is a right side elevational view thereof;
FIG. 3 is a left side elevational view thereof;
FIG. 4 is a rear elevational view thereof;
FIG. 5 is a top plan view thereof; and
FIG. 6 is a bottom view thereof.



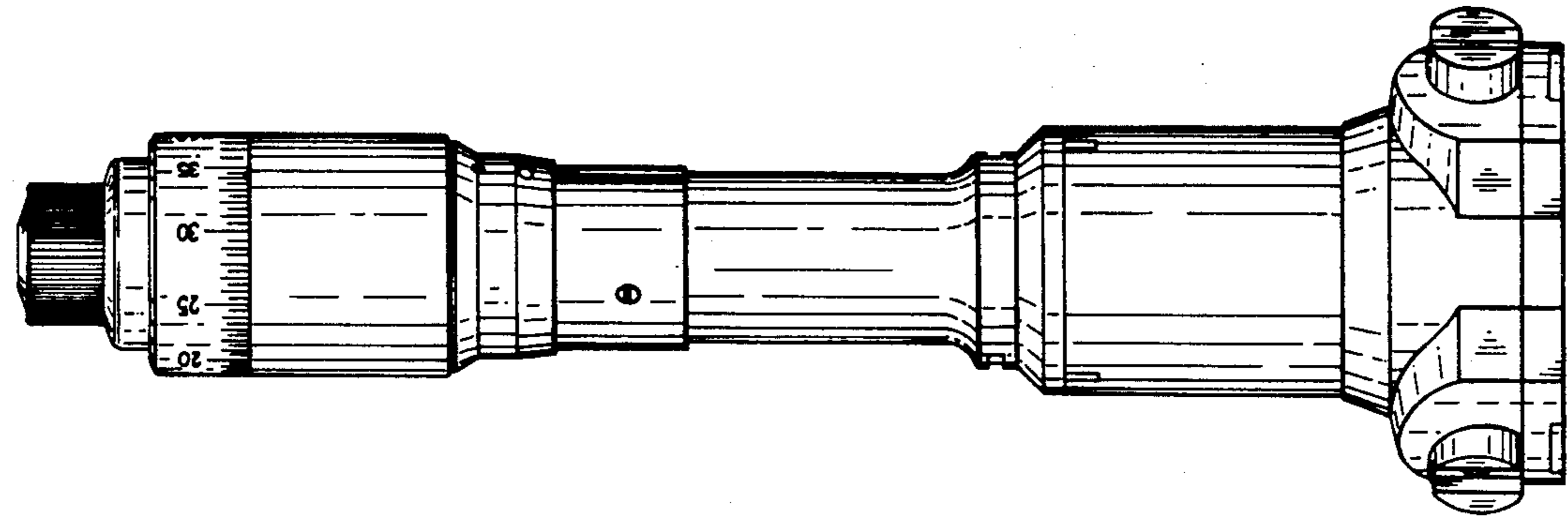


FIG. 4

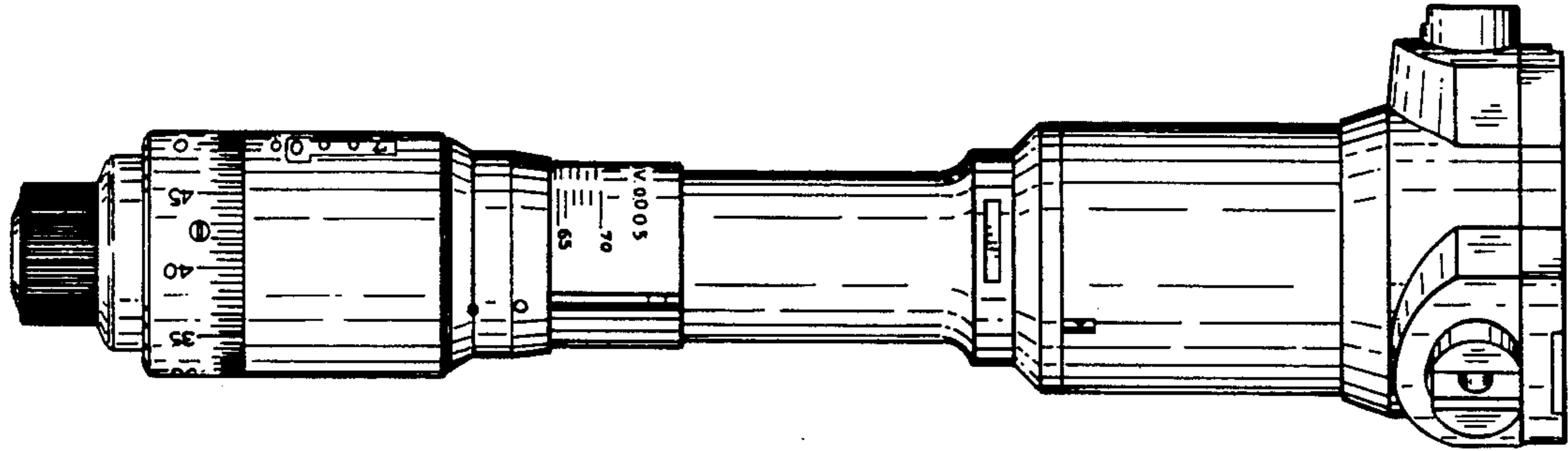


FIG. 3

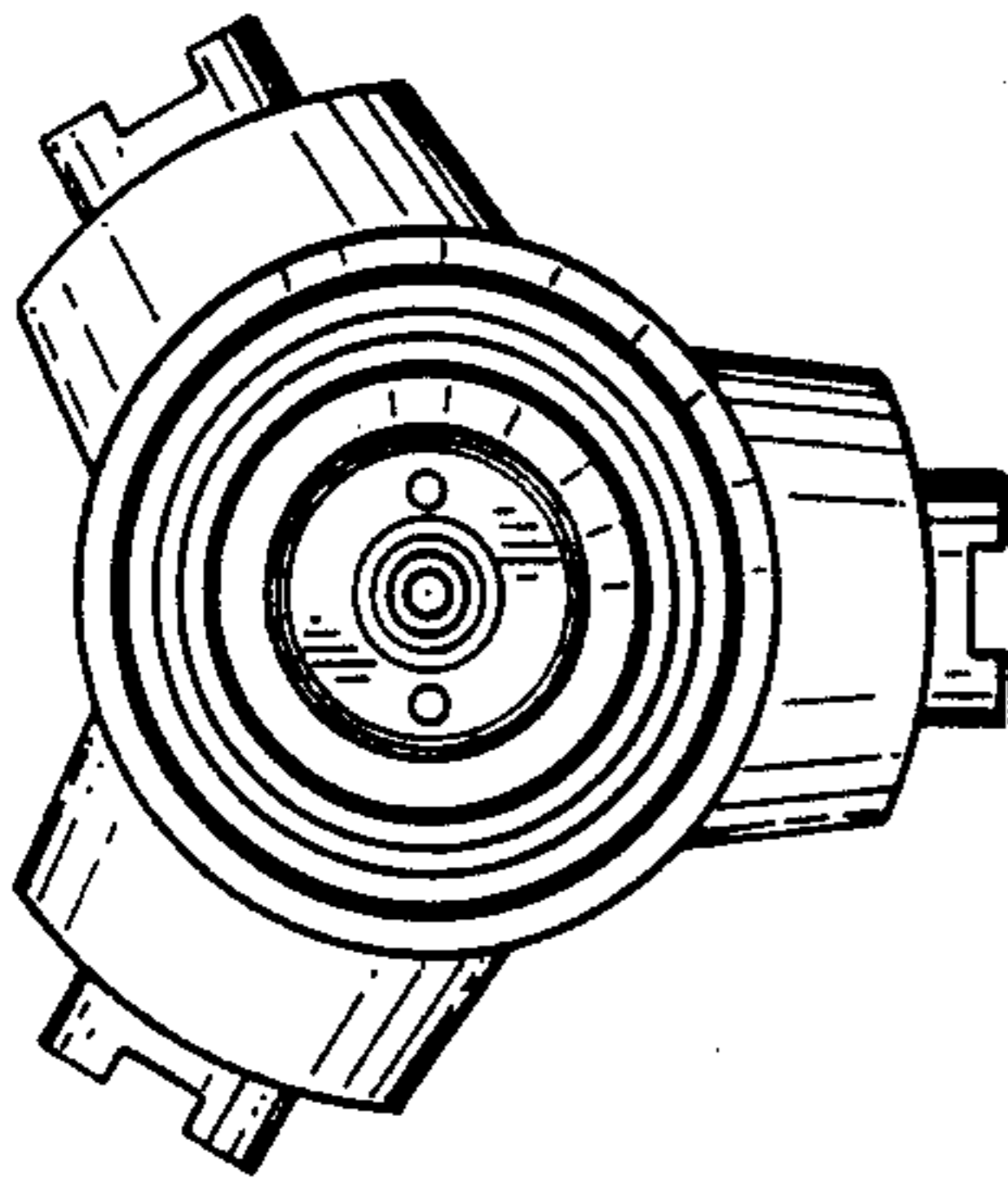


FIG. 5

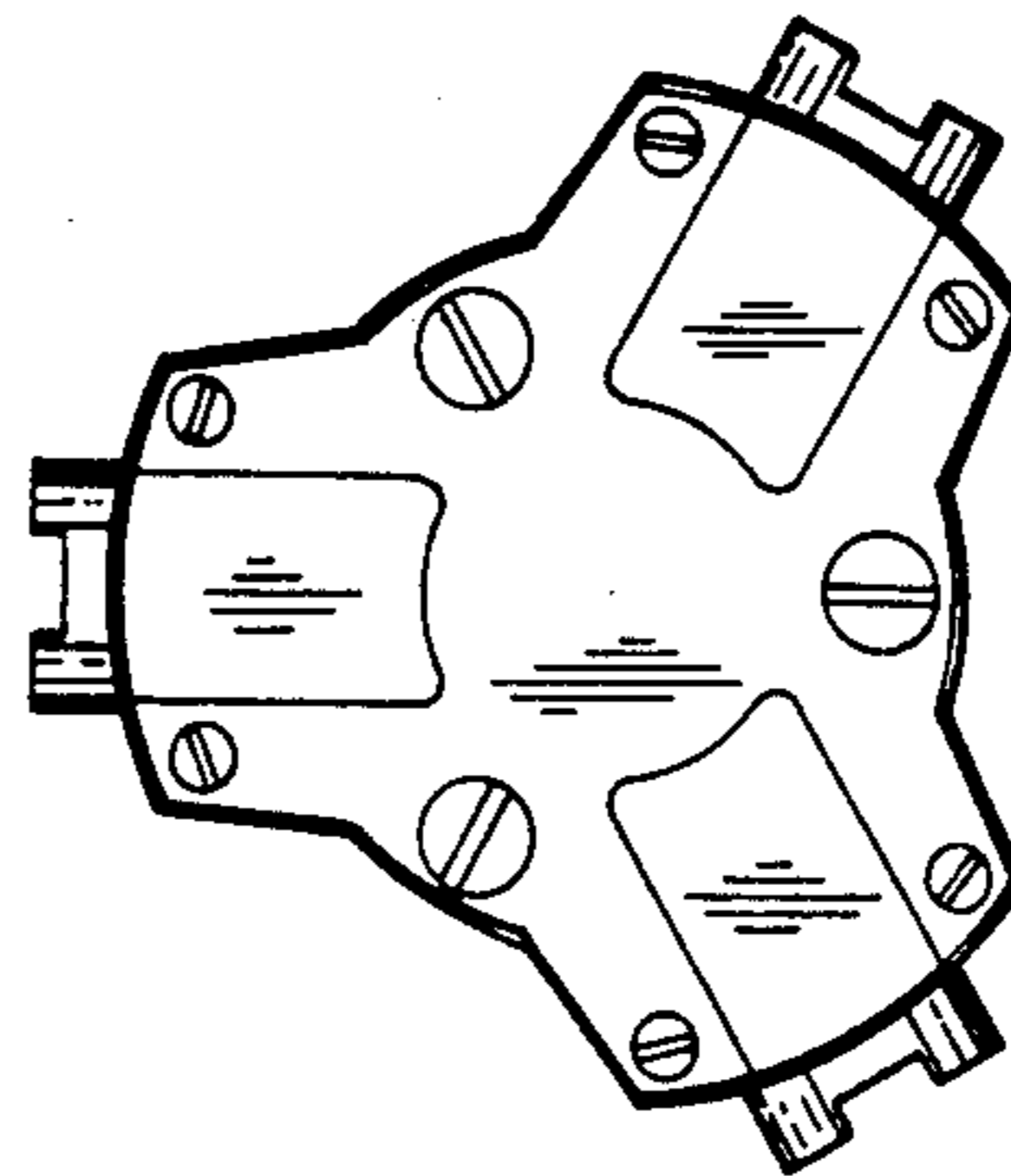


FIG. 6

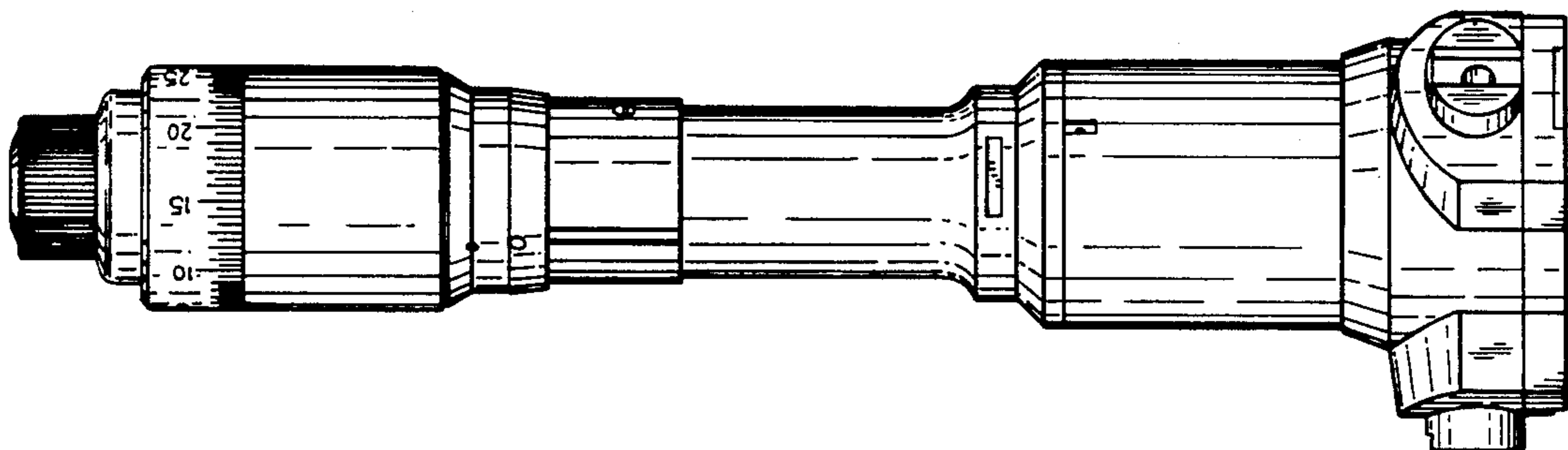


FIG. 2

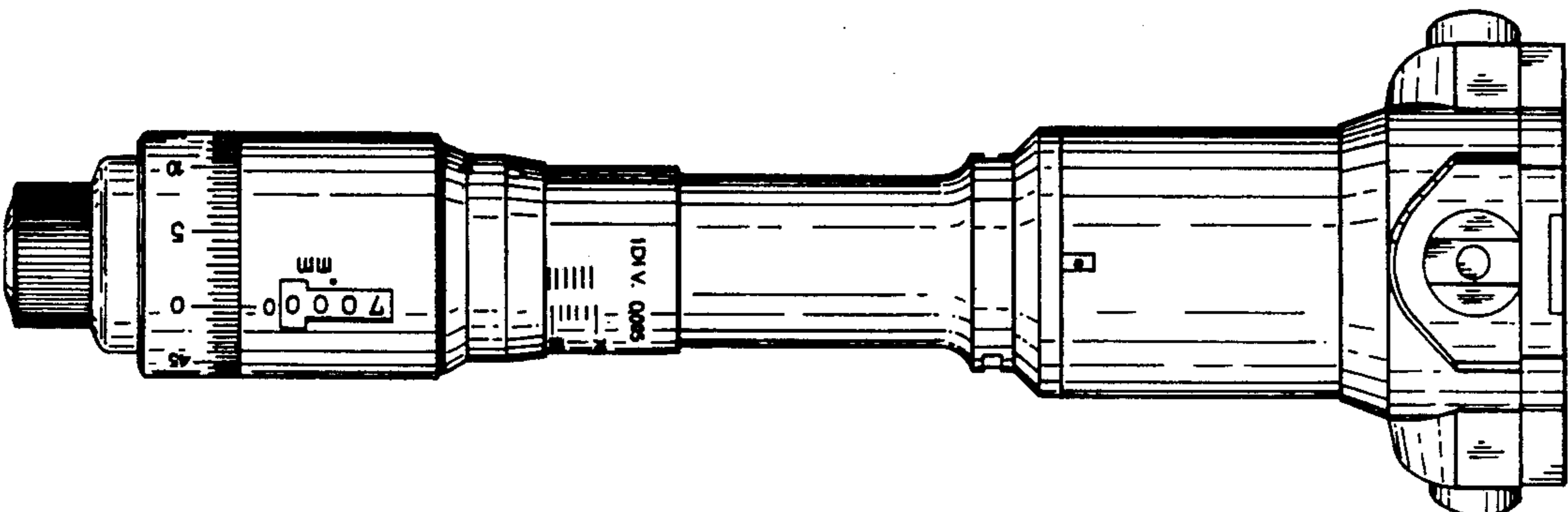


FIG. 1